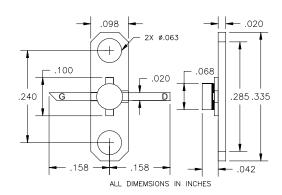


# **EFA040A-100P**

## **Low Distortion GaAs Power FET**

### **UPDATED 11/17/2006**

- NON-HERMETIC 100MIL METAL FLANGE PACKAGE
- +23.0dBm TYPICAL OUTPUT POWER
- 9.0dB TYPICAL POWER GAIN AT 12GHz
- 0.3 X 400 MICRON RECESSED "MUSHROOM" GATE
- Si<sub>3</sub>N<sub>4</sub> PASSIVATION
- ADVANCED EPITAXIAL HETEROJUNCTION PROFILE PROVIDES HIGH POWER EFFICIENCY, LINEARITY AND RELIABILITY



## ELECTRICAL CHARACTERISTICS (T<sub>a</sub> = 25 °C)

SYMBOLS	PARAMETERS/TEST CONDITIONS	MIN	TYP	MAX	UNIT
P <sub>1dB</sub>	Output Power at 1dB Compression $V_{DS} = 8V$ , $V_{DS} \approx 50\%$ $V_{DS} = 8V$ , $V_{DS} \approx 50\%$ $V_{DS} = 12$ $V_{DS} \approx 12$ $V_{DS} \approx 12$	21.0	23.0 23.0		dBm
G <sub>1dB</sub>		7.5	9.0 6.5		dB
PAE	Power Added Efficiency at 1dB Compression $V_{DS} = 8V$ , $I_{DS} \approx 50\%$ $I_{DSS}$ f=12GHz		35		%
I <sub>DSS</sub>	Saturated Drain Current V <sub>DS</sub> = 3 V, V <sub>GS</sub> = 0 V	60	105	160	mA
G <sub>M</sub>	Transconductance $V_{DS} = 3 \text{ V}, V_{GS} = 0 \text{ V}$	45	60		mS
V <sub>P</sub>	Pinch-off Voltage V <sub>DS</sub> = 3 V, I <sub>DS</sub> = 1.0 mA		-2.0	-3.5	V
BV <sub>GD</sub>	Drain Breakdown Voltage I <sub>GD</sub> = 1.0mA	-13	-15		V
BV <sub>GS</sub>	Source Breakdown Voltage I <sub>GS</sub> = 1.0mA	-7	-14		V
R <sub>TH</sub>	Thermal Resistance (Au-Sn Eutectic Attach)		115*		°C/W

Note: \* Overall Rth depends on case mounting.

## MAXIMUM RATINGS AT 25°C

SYMBOLS	PARAMETERS	ABSOLUTE <sup>1</sup>	CONTINUOUS <sup>2</sup>
V <sub>DS</sub>	Drain-Source Voltage	12V	8V
$V_{GS}$	Gate-Source Voltage	-5V	-4V
lgf	Forward Gate Current	1.8 mA	0.6 mA
lgr	Reverse Gate Current	0.3 mA	0.1 mA
Pin	Input Power	20 dBm	@ 3dB Compression
Tch	Channel Temperature	175°C	175°C
Tstg	Storage Temperature	-65/175°C	-65/175°C
Pt	Total Power Dissipation	1.2 W	1.2 W

Note: 1. Exceeding any of the above ratings may result in permanent damage.

<sup>2.</sup> Exceeding any of the above ratings may reduce MTTF below design goals.



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- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness